Frequency
Every year

Summary
This intensive course is intended for researchers who envisage to use scanning electron microscopy techniques for their research or who want to understand how to interpret SEM images and analytical results presented in scientific publications.

Content
This intensive course is intended for researchers who are potential new users of scanning electron microscopes. It will provide them with a basic understanding of the instruments, optics of SEM, the imaging modes, the associated analytical techniques EDS and EBSD, related theories of image formation. Demonstrations will be given on the microscopes.
2x Year Spring (b) and autumn (a).

Keywords
SEM, FIB, ESEM

Assessment methods
Written

Resources
Websites
• https://www.epfl.ch/research/facilities/cime/teaching/doctoralschools/mse-636/